

Notice of References Cited		Application/Control No. 10/721,850	Applicant(s)/Patent Under Reexamination DE KONING, PETRUS T.
		Examiner JACKY X. ZHENG	Art Unit 2625

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-4,849,788 A	07-1989	Prebola, Jay M.	399/372
*	B US-5,328,163 A	07-1994	Yamada, Yasushi	271/10.01
*	C US-5,338,018 A	08-1994	Nagao et al.	271/3.05
*	D US-5,488,464 A	01-1996	Wenthe et al.	399/396
*	E US-5,515,153 A	05-1996	Tokunoh, Yoshiaki	399/374
*	F US-5,610,731 A	03-1997	Itoh, Yoshiya	358/496
*	G US-5,734,483 A	03-1998	Itoh, Yoshiya	358/496
*	H US-5,912,747 A	06-1999	Murakami, Hiroshi	358/497
*	I US-5,953,574 A	09-1999	Okada, Tamotsu	399/374
*	J US-6,027,109 A	02-2000	Wada et al.	271/3.14
*	K US-2001/0033761 A1	10-2001	Takida et al.	399/367
*	L US-2002/0033968 A1	03-2002	Chen, Michael	358/406
*	M US-2002/0044305 A1	04-2002	KAWAI et al.	358/474

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N				
*	O				
*	P				
*	Q				
*	R				
*	S				
*	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U
*	V
*	W
*	X

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0057465 A1	05-2002	Anzai, Toshiaki	358/474
*	B US-2002/0080429 A1	06-2002	Honbo et al.	358/505
*	C US-2002/0135120 A1	09-2002	de Koning et al.	271/10.01
*	D US-2002/0135821 A1	09-2002	Sekine, Noriaki	358/498
*	E US-2002/0176122 A1	11-2002	Mui et al.	358/504
*	F US-2002/0164175 A1	11-2002	Kinoshita, Hidehiko	399/67
*	G US-2003/0011121 A1	01-2003	Kobayashi et al.	271/3.14
*	H US-6,512,602 B1	01-2003	Sheng et al.	358/498
*	I US-2003/0026633 A1	02-2003	Nakagawa et al.	399/367
*	J US-2003/0081275 A1	05-2003	Shishido, Kazuo	358/509
*	K US-2003/0090052 A1	05-2003	Hsiao et al.	271/114
*	L US-6,595,512 B2	07-2003	de Koning et al.	271/125
*	M US-6,618,575 B2	09-2003	Takida et al.	399/367

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

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2625

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2004/0004320 A1	01-2004	Watanabe et al.	271/10.01
*	B US-2004/0004319 A1	01-2004	Hattori et al.	271/10.01
*	C US-2004/0047007 A1	03-2004	Kanno, Tohru	358/474
*	D US-2004/0062579 A1	04-2004	Iwago et al.	399/367
*	E US-2004/0065991 A1	04-2004	Watanabe et al.	271/010.01
*	F US-6,738,167 B1	05-2004	Suzuki, Kazuhiro	358/498
*	G US-2004/0125412 A1	07-2004	Sugeta, Mitsuhiro	358/003.26
*	H US-6,874,778 B2	04-2005	Nakano et al.	271/111
*	I US-2005/0111059 A1	05-2005	de Koning, Petrus T.	358/498
*	J US-6,947,187 B2	09-2005	Mui et al.	358/496
*	K US-7,021,618 B2	04-2006	Watanabe et al.	271/3.14
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
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